

<b>Notice of References Cited</b>	Application/Control No. 10/091,206	Applicant(s)/Patent Under Reexamination BANTZ ET AL.	
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	B	US-6,590,981	07-2003	Fruehauf et al.	380/260
	C	US-5,369,706	11-1994	Latka, David S.	380/262
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	F	US-6,185,307	02-2001	Johnson, Jr., William S.	380/270
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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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